Se	aı	cl	h-I	V.	nt	20
	uı				-	



Application/Control No

10/712,136 Examiner

Khanh V. Nguyen

Applicant(s)/Patent under Reexamination

SNIDER ET AL.

Art Unit

2817

SEARCHED					
Class	Subclass	Date	Examiner		
330	85, 138, 140, 279, 290	1/28/2005	NKV		
ABOVE	UPDATED	7/8/2005	NKV _.		
		•			
		-			

INTERFERENCE SEARCHED						
Subclass	Date	Examiner				
ABOVE	7/8/2005	NKV				
		-				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see history printout)	7/8/2005	NKV			
		_			
	·				